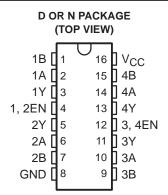
SLLS046C - JANUARY 1989 - REVISED MAY 1995

- Meets or Exceeds the Requirements of ITU Recommendations V.10, V.11, X.26, and X.27
- Designed to Operate Up To 20 Mbaud
- –7 V to 7 V Common-Mode Input Voltage Range With 300-mV Sensitivity
- 3-State TTL-Compatible Outputs
- High Input Impedance . . . 12 kΩ Min
- Input Hysteresis . . . 120 mV Typ
- Single 5-V Supply Operation
- Low Supply Current Requirement 35 mA Max
- Improved Speed and Power Consumption Compared to MC3486



description

The SN75ALS199 is a monolithic, quadruple line receiver with 3-state outputs designed using advanced, low-power, Schottky technology. This technology provides combined improvements in bar design, tooling production, and wafer fabrication, providing significantly less power consumption and permitting much higher data throughput than other designs. The device meets the specification of ITU Recommendations V.10, V.11, X.26, and X.27.

The SN75ALS199 features 3-state outputs that permit direct connection to a bus-organized system with a fail-safe design that ensures the outputs will always be high if the inputs are open. The device is optimized for balanced multipoint bus transmission at rates up to 20 megabits per second. The input features high-input impedance, input hysteresis for increased noise immunity, and an input sensitivity of ± 300 mV over a common-mode input voltage range of ± 7 V. It also features an active-high enable function for each of two receiver pairs. The SN75ALS199 is designed for optimum performance when used with the SN75ALS194 quadruple, differential line driver.

The SN75ALS199 is characterized for operation from 0°C to 70°C.

FUNCTION TABLE (each receiver)

DIFFERENTIAL INPUTS A-B	EN	OUTPUT Y
V _{ID} ≥ 0.3 V	Н	Н
$-0.3 \text{ V} < \text{V}_{1D} < 0.3 \text{ V}$	Н	?
$V_{ID} \le -0.3 V$	Н	L
X	L	Z
Open	Н	н

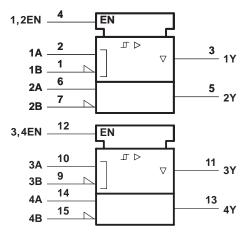
H = high level, L = low level, X = irrelevant, ? = indeterminate, Z = high impedance (off)



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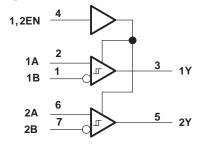


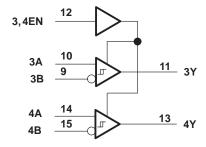
logic symbol†



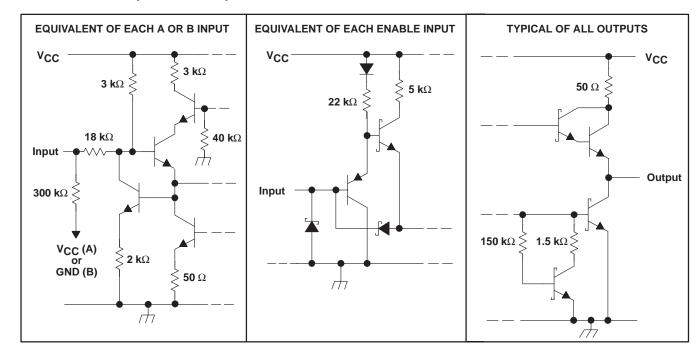
[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram





schematics of inputs and outputs



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC} (see Note 1)	
Input voltage, V _I (A or B inputs)	
Differential input voltage, V _{ID} (see Note 2)	±15 V
Enable input voltage, V _I	
Low-level output current, I _{OL}	50 mA
Continuous total dissipation	See Dissipation Rating Table
Operating free-air temperature range, T _A	0°C to 70°C
Storage temperature range, T _{stg}	– 65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

2. Differential input voltage is measured at the noninverting input with respect to the corresponding inverting input.

DISSIPATION RATING TABLE

PACKAGE	T _A ≤ 25°C POWER RATING	DERATING FACTOR	T _A = 70°C POWER RATING
D	950 mW	7.6 mW/°C	608 mW
N	1150 mW	9.2 mW/°C	736 mW

recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V _{CC}	4.75	5	5.25	V
Common-mode input voltage, V _{IC}			±7	V
Differential input voltage, V _{ID}			±12	V
High-level input voltage, VIH	2			V
Low-level input voltage, V _{IL}			0.8	V
High-level output current, I _{OH}			- 400	μΑ
Low-level output current, IOL			16	mA
Operating free-air temperature, T _A	0		70	°C



NOTES: 1. All voltage values, except differential input voltage, are with respect to network ground terminal.

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electrical characteristics over recommended ranges of common-mode input voltage, supply voltage, and operating free-air temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP [†]	MAX	UNIT	
V _{IT+}	Positive-going input threshold voltage					300	mV	
VIT-	Negative-going input threshold voltage			-300‡			mV	
V _{hys}	Hysteresis voltage (V _{IT+} – V _{IT-})				120		mV	
٧ıK	Enable-input clamp voltage	$I_{I} = -18 \text{ mA}$				-1.5	V	
VOH	High-level output voltage	$V_{ID} = 300 \text{ mV},$	$I_{OH} = -400 \mu A$	2.7	3.6		V	
Vai	Low-level output voltage	V _{ID} = - 300 mV	I _{OL} = 8 mA			0.45	V	
VOL			I _{OL} = 16 mA			0.5		
107	High-impedance-state output current	$V_{IL} = 0.8 \text{ V}, V_{ID} = -3 \text{ V},$	$V_0 = 2.7 \text{ V}$			20	μА	
loz		$V_{IL} = 0.8 \text{ V}, V_{IO} = 3 \text{ V},$	$V_0 = 0.5 V$			-20	μΑ	
١,	Line input current	Other input at 0 V, See Note 3	V _I = 15 V		0.7	1.2	mA	
11			V _I = −15 V		-1	-1.7	IIIA	
ı	High-level enable-input current		V _{IH} = 2.7 V			20	μΑ	
ΊΗ			V _{IH} = 5.25 V			100	μΑ	
IլL	Low-level enable-input current	V _{IL} = 0.4 V				-100	μΑ	
	Input resistance			12	18	·	kΩ	
los	Short-circuit output current§	V _{ID} = 3 V,	VO = 0	-15	-78	-130	mA	
Icc	Supply current	Outputs disabled			22	35	mA	

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

switching characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

	PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	UNIT
^t PLH	Propagation delay time, low- to high-level output	$V_{ID} = 0 V \text{ to } 3 V,$	$C_L = 15 pF$,		15	22	ns
^t PHL	Propagation delay time, high- to low-level output	See Figure 2	_		15	22	115
^t PZH	Output enable time to high level	C _I = 15 pF,	See Figure 3		13	25	20
tPZL	Output enable time to low level	CL = 15 pr,	See Figure 3		11	25	ns
tPHZ	Output disable time from high level	C _I = 15 pF,	See Figure 3		13	25	20
t _{PLZ}	Output disable time from low level	CL = 15 pr,	See Figure 3		15	22	ns



[‡] The algebraic convention, in which the less positive limit is designated minimum, is used in this data sheet for threshold voltage levels only.

[§] Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

NOTE 3: Refer to ITU Recommendations V.10 and V.11 for exact conditions.

PARAMETER MEASUREMENT INFORMATION

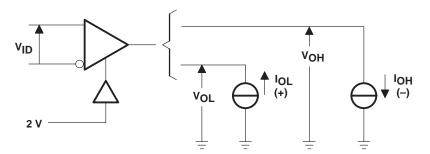
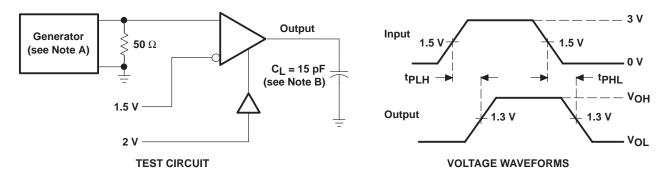


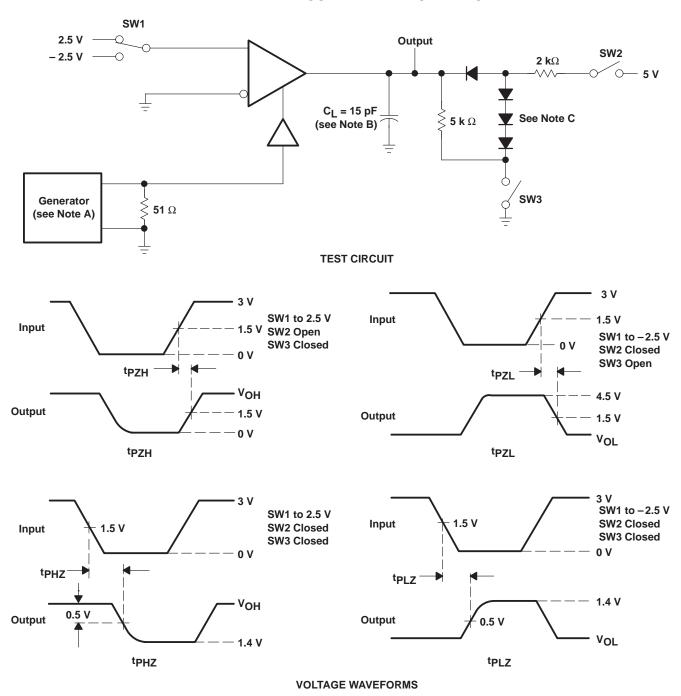
Figure 1. V_{OH} and V_{OL} Test Circuit



- NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 1 MHz, duty cycle \leq 50%, Z_O = 50 Ω , $t_f \leq$ 6 ns, $t_f \leq$ 6 ns.
 - B. C_L includes probe and jig capacitance.

Figure 2. Test Circuit and Voltage Waveforms

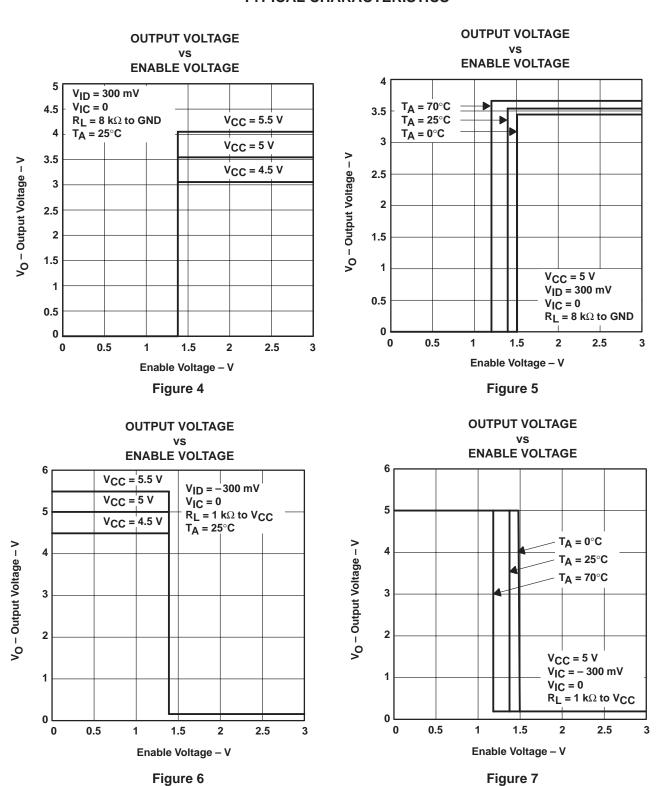
PARAMETER MEASUREMENT INFORMATION



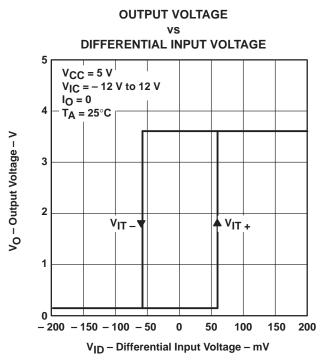
- NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 1 MHz, duty cycle \leq 50%, Z_O = 50 Ω , $t_f \leq$ 6 ns, $t_f \leq$ 6 ns.
 - B. C_L includes probe and jig capacitance.
 - C. All diodes are 1N3064 or equivalent.

Figure 3. Test Circuit and Voltage Waveforms











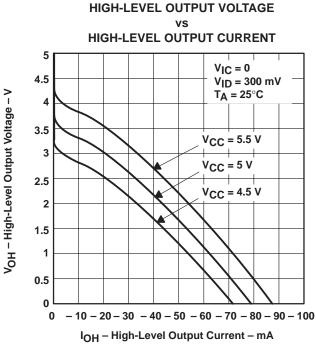


Figure 10

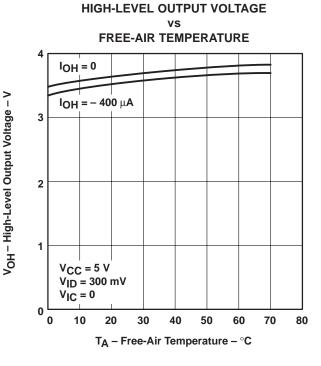


Figure 9

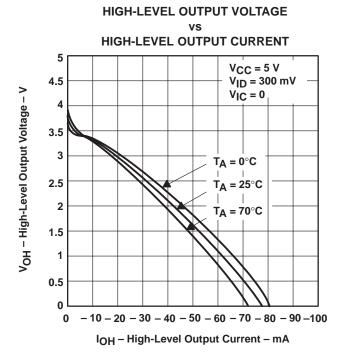


Figure 11



LOW-LEVEL OUTPUT VOLTAGE

FREE-AIR TEMPERATURE

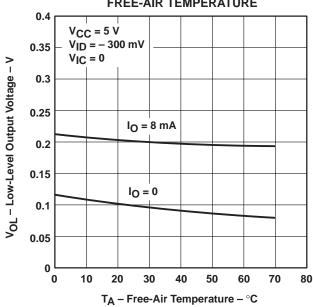


Figure 12

LOW-LEVEL OUTPUT VOLTAGE

vs

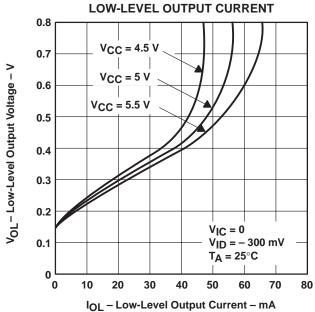


Figure 13

LOW-LEVEL OUTPUT VOLTAGE

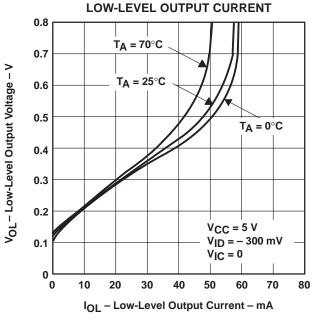


Figure 14

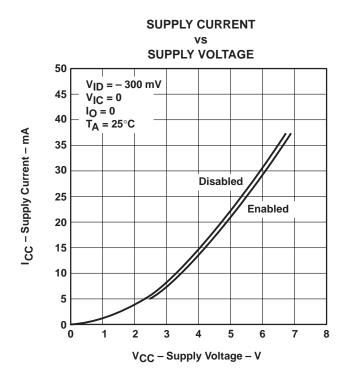


Figure 15

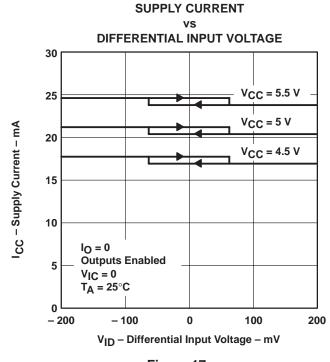


Figure 17

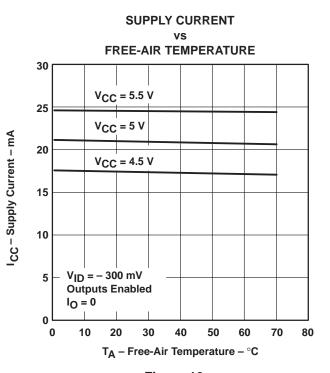
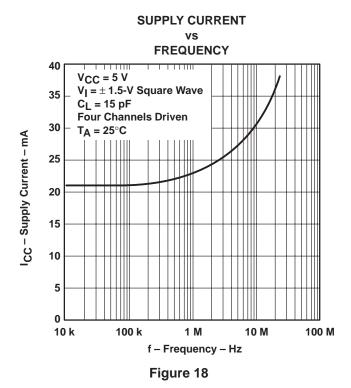
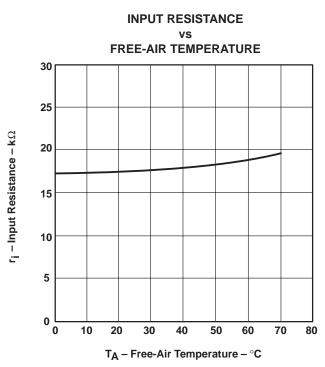


Figure 16





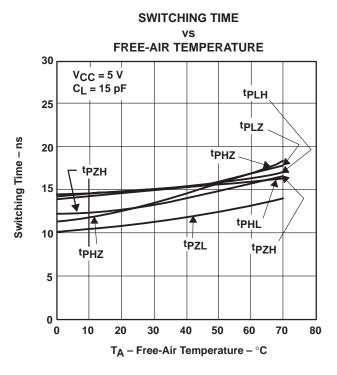
INPUT CURRENT



INPUT VOLTAGE TO GND 3 T_A = 25°C 2 - Input Current - mA 1 0 -1 - 2 -3 - 20 - 15 - 10 - 5 0 5 10 15 20 VI - Input Voltage to GND - V

Figure 19

Figure 20



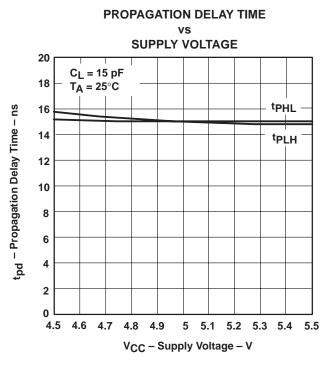


Figure 21

Figure 22

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